

Shu-Zee Alencious Lo

List of Publications by Year in descending order

Source: <https://exaly.com/author-pdf/3797693/publications.pdf>

Version: 2024-02-01

12
papers

471
citations

1307594

7
h-index

1372567

10
g-index

12
all docs

12
docs citations

12
times ranked

1115
citing authors

#	ARTICLE	IF	CITATIONS
1	Polaron self-localization in white-light emitting hybrid perovskites. Journal of Materials Chemistry C, 2017, 5, 2771-2780.	5.5	196
2	Self-assembled hierarchical nanostructured perovskites enable highly efficient LEDs <i>via</i> an energy cascade. Energy and Environmental Science, 2018, 11, 1770-1778.	30.8	135
3	Nanoporous silicon multilayers for terahertz filtering. Optics Letters, 2009, 34, 2921.	3.3	33
4	Large Polaron Self-Trapped States in Three-Dimensional Metal-Halide Perovskites. , 2020, 2, 20-27.		33
5	Imaging local index variations in an optical waveguide using a tapping-mode near-field scanning optical microscope. Applied Physics Letters, 1999, 75, 1039-1041.	3.3	25
6	Optical NP problem solver on laser-written waveguide platform. Optics Express, 2018, 26, 702.	3.4	16
7	Terahertz surface plasmon propagation in nanoporous silicon layers. Applied Physics Letters, 2010, 96, .	3.3	13
8	Terahertz transmission through porous silicon membranes. Physica Status Solidi (A) Applications and Materials Science, 2009, 206, 1273-1277.	1.8	7
9	Application of nanoporous silicon substrates for terahertz spectroscopy. Optical Materials Express, 2013, 3, 114.	3.0	6
10	Pulse propagation in hollow-core fiber at high-pressure regime: application to compression of tens of μJ pulses and determination of nonlinear refractive index of xenon at $103\ \mu\text{m}$. Applied Optics, 2018, 57, 4659.		6
11	Pulse propagation in hollow-core fiber at high-pressure regime: application to compression of tens of μJ pulses and determination of nonlinear refractive index of xenon at $103\ \mu\text{m}$: publisher's note. Applied Optics, 2018, 57, 6496.		1
12	Pulsed terahertz bi-directional reflection distribution function (BRDF) measurements of materials and obscurants. Proceedings of SPIE, 2011, , .	0.8	0